		Application/Control No.	Applicant(s	Applicant(s)/Patent under Reexamination
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	ORIGINAL		INTERNATION	INTERNATIONAL CLASSIFICATION
CLASS	S	SUBCLASS	CLAIMED	NON-CLAIMED
345	39	652	00/9 9 6 0 9	
	CROSS REFERENCE(S)	ICE(S)		
CLASS	SUBCLASS (ONE SUBCLASS	JBCLASS PER BLOCK)		
345	651 660	661 677 815	,	
TA-M WAIV (Assistant Examiner)	9/1/2006 (Date)			Total Claims Allowed:
Wilne Examiner (Legal Instruments Examiner)	to 9/29/06 (Date)	(Primary Examiner)	KEE M. TUNG SUPERVISORY PATENT EXAMINER (06	O.G. O.G. Print Claim(s) Print Figure

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